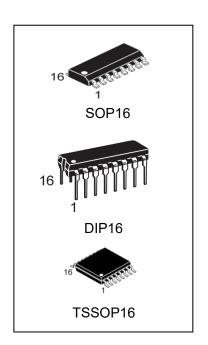


# 4-BIT SYNCHRONOUS UP/DPWN COUNTERS (DUAL CLOCK WITH CLEAR)

#### **FEATURES**

- Wide Operating Voltage Range of 2 V to 6 V
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption, 80-µA Max ICC
- Typical tpd = 20 ns
- ±4-mA Output Drive at 5 V
- Low Input Current of 1 μA Max
- Look-Ahead Circuitry Enhances Cascaded Counters
- Fully Synchronous in Count Modes
- Parallel Asynchronous Load for Modulo-N Count Lengths
- Asynchronous Clear



#### ORDERING INFORMATION

DEVICE	Package Type	MARKING	Packing	Packing Qty
74HC193N	DIP16	74HC193	TUBE	1000pcs/Box
74HC193M/TR	SOP16	74HC193	REEL	2500pcs/Reel
74HC193MT/TR	TSSOP16	HC193	REEL	2500pcs/Reel



#### **Description**

The 74HC193 devices are 4-bit synchronous, reversible, up/down binary counters. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincidentally with each other when so instructed by the steering logic. This mode of operation eliminates the output counting spikes normally associated with asynchronous (ripple-clock) counters.

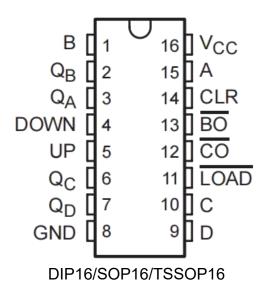
The outputs of the four flip-flops are triggered on a low-to-high-level transition of either count (clock) input (UP or DOWN). The direction of counting is determined by which count input is pulsed while the other count input is high.

All four counters are fully programmable; that is, each output may be preset to either level by placing a low on the load  $(\overline{LOAD})$  input and entering the desired data at the data inputs. The output changes to agree with the data inputs independently of the count pulses. This feature allows the counters to be used as modulo-N dividers simply by modifying the count length with the preset inputs.

A clear (CLR) input has been provided that forces all outputs to the low level when a high level is applied. The clear function is independent of the count and  $\overline{\mathsf{LOAD}}$  inputs.

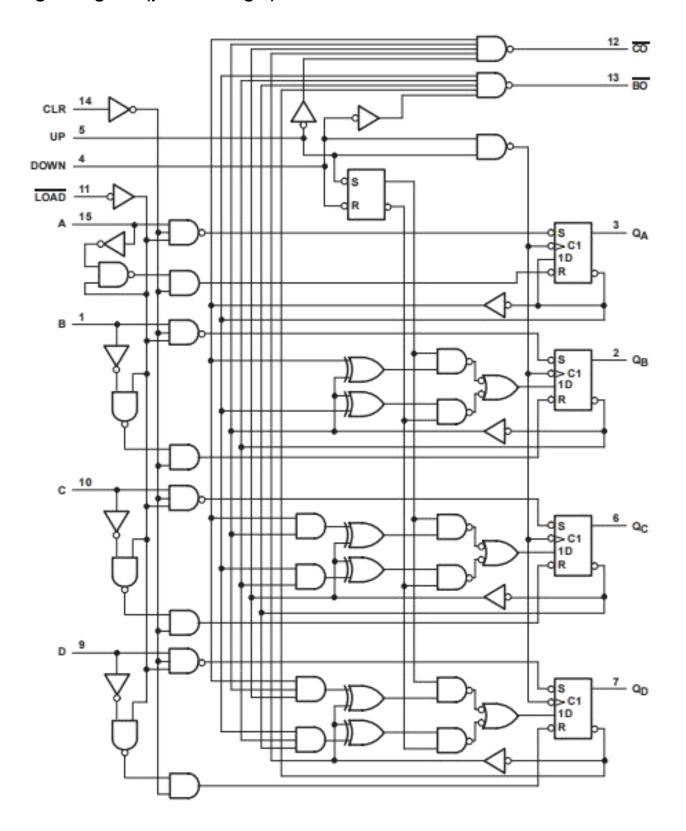
These counters were designed to be cascaded without the need for external circuitry. The borrow ( $\overline{BO}$ ) output produces a low-level pulse while the count is zero (all outputs low) and DOWN is low. Similarly, the carry ( $\overline{CO}$ ) output produces a low-level pulse while the count is maximum (9 or 15), and UP is low. The counters then can be cascaded easily by feeding  $\overline{BO}$  and  $\overline{CO}$  to DOWN and UP, respectively, of the succeeding counter.

#### **Pin Configuration**





### logic diagram (positive logic)

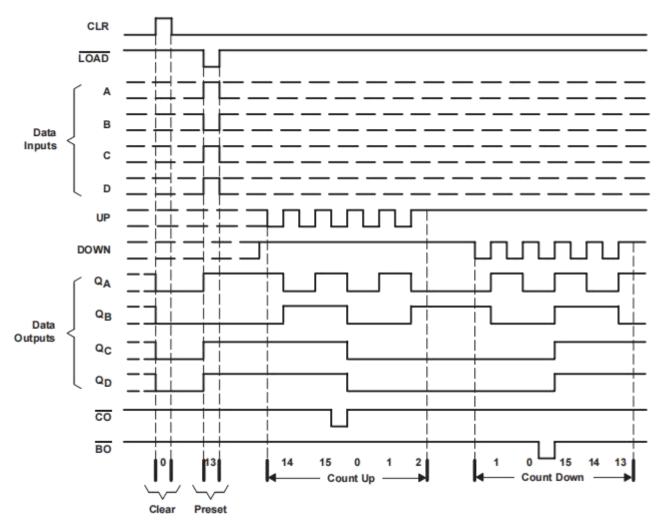




#### typical clear, load, and count sequence

The following sequence is illustrated below:

- 1. Clear outputs to 0
- 2. Load (preset) to binary 13
- 3. Count up to 14, 15, carry, 0, 1, and 2
- 4. Count down to 1, 0, borrow, 15, 14, and 13



NOTES: A. CLR overrides  $\overline{\text{LOAD}}$ , data, and count inputs.

B. When counting up, count-down input must be high; when counting down, count-up input must be high.



#### absolute maximum ratings over operating free-air temperature range

(unless otherwise noted)

Condi	tion	Min	Max	
Supply voltage range,VCC		-0.5V	7V	
Input clamp current IIK(VI<0 or VI>	VCC)(see Note 1)	-20mA	+20mA	
Output clamp current,IO(Vo<0 or V	o>VCC)(see Note 1)	-20mA	+20mA	
Continuous output current,IO(VO=0	to VCC)	-25mA	+25mA	
Continuous current through VCC o	r GND	-50mA	+50mA	
	M package	-	73°C/W	
Package thermal impedance,	N package	-	67°C/W	
θJA (see Note 2):	MT package	-	108°C/W	
Storage temperature range,Tstg		-65°C	150°C	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. NOTES:

- 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 2. The package thermal impedance is calculated in accordance with JESD 51-7.

#### recommended operating conditions (see Note 3)

			-	74HC193	3	UNIT
			MIN	NOM	MAX	
VCC	Supply voltage		2	5	6	V
		VCC = 2 V	1.5			
VIH	High-level input voltage	VCC = 4.5 V	3.15			V
		VCC = 6 V	4.2			V
	Low-level input voltage	VCC = 2 V			0.5	
VIL		VCC = 4.5 V			1.35	V
		VCC = 6 V			1.8	V
VI	Input voltage		0		VCC	V
VO	Output voltage		0		VCC	V
		VCC = 2 V			1000	
t/∆v‡	Input transition rise/fall time	VCC = 4.5 V			500	ns
		VCC = 6 V			400	
TA	Operating free-air temperature		-40		85	°C

NOTE 3: All unused inputs of the device must be held at VCC or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

‡ If this device is used in the threshold region (from VILmax = 0.5 V to VIHmin = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at tt = 1000 ns and VCC = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.



## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	vcc	1	TA = 25°C	3	74HC193		UNIT					
PARAMETER	TEST CO	NDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT					
								2 V	1.9	1.998		1.9		
VOH VI = VIH or		IOH = −20 A	4.5 V	4.4	4.499		4.4							
	VI = VIH or VIL		6 V	5.9	5.999		5.9		V					
		IOH = −4 mA	4.5 V	3.98	4.3		3.84							
		IOH = −5.2 mA	6 V	5.48	5.8		5.34							
			2 V		0.002	0.1		0.1						
		IOL = 20 A	4.5 V		0.00	0.1		0.1						
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1	V					
		IOL = 4 mA	4.5 V		0.17	0.26		0.33						
		IOL = 5.2 mA	6 V		0.15	0.26		0.33						
II	VI = V	6 V		±0.1	±100		±1000	nA						
ICC	VI = VCC	or 0,IO = 0	6 V			8		80	μΑ					
Ci			2 V to 6 V		3	10		10	pF					

#### timing requirements over recommended operating free-air temperature range

(unless otherwise noted)

		vcc	TA =	25°C	74HC193		UNIT
		VCC	MIN	MAX	MIN	MAX	UNII
		2 V		4.2		3.3	
fclock Clock frequency		4.5 V		21		17	MHz
		6 V		24		19	
		2 V	120		150		
	CLR high	4.5 V	24		30		
		6 V	21		26		
		2 V	120		150		
tw Pulse duration	LOAD low	4.5 V	24		30		ns
		6 V	21		26		
		2 V	120		150		
	UP or DOWN high or low	4.5 V	24		30		
		6 V	21		26		
		2 V	110		140		
	Data before <del>LOAD</del> inactive	4.5 V	22		28		
		6 V	19		24		
		2 V	110		140		
tsu Setup time	CLR inactive before UP↑ or DOWN	4.5 V	22		28		
		6 V	19		24		
		2 V	110		140		ns
	TOAD inactive before UP↑ or DOWN	4.5 V	22		28		113
		6 V	19		24		
		2 V	5		5		
th Hold time	Data after <del>LOAD</del> inactive	4.5 V	5		5		ns
		6 V	5		5		



# switching characteristics over recommended operating free-air temperature range, CL = 50 pF

(unless otherwise noted) (see Figure 1)

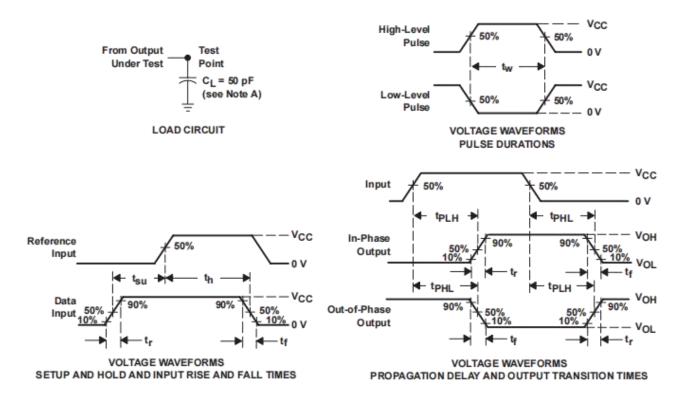
DADAMETED	EDOM (INDUE)	TO (OUTPUT)	\ \vac		TA = 25°	C	74HC193		UNIT
PARAMETER	FROM (INPUT)	TO (OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	UNII
			2 V	4.2	8		3.3		
fmax			4.5 V	21	55		17		MHz
			6 V	24	60		19		
			2 V		75	165		205	
	UP	со	4.5 V		24	33		41	
			6 V		20	28		35	
			2 V		75	165		205	
An d	DOWN	ВО	4.5 V		24	33		41	ns
			6 V		20	28		35	
tpd			2 V		190	250		315	
	UP or DOWN	Any Q	4.5 V		40	50		63	
			6 V		35	43		54	
			2 V		190	260		325	
	LOAD	Any Q	4.5 V		40	52		65	
			6 V		35	44		55	
			2 V		170	240		300	
tPHL	CLR	Any Q	4.5 V		36	48		60	ns
			6 V		31	41		51	
			2 V		38	75		95	ns
tt		Any	4.5 V		8	15		19	
			6 V		6	13		16	

#### operating characteristics, TA = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	No load	50	pF



#### PARAMETER MEASUREMENT INFORMATION



#### NOTES:

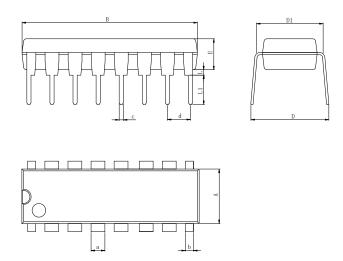
- A. CL includes probe and test-fixture capacitance.
- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz, ZO = 50  $\Omega$ , tr = 6 ns, tf = 6 ns.
- C. For clock inputs, fmax is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tPLH and tPHL are the same as tpd.

Figure 1. Load Circuit and Voltage Wave forms



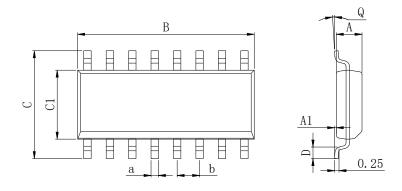
### **Physical Dimensions**

#### DIP16



Dimensions In Millimeters(DIP16)											
Symbol:	Α	В	D	D1	Е	L	L1	а	b	С	d
Min:	6.10	18.94	8.40	7.42	3.10	0.50	300	1.50	0.85	0.40	0.54.000
Max:	6.68	19.56	9.00	7.82	3.55	0.70	3.60	1.55	0.90	0.50	2.54 BSC

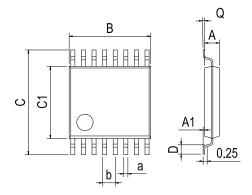
#### SOP16



Dimensions In Millimeters(SOP16)										
Symbol:	Α	A1	В	С	C1	D	Q	а	b	
Min:	1.35	0.05	9.80	5.80	3.80	0.40	0°	0.35	1.27 BSC	
Max:	1.55	0.20	10.0	6.20	4.00	0.80	8°	0.45	1.27 650	



#### TSSOP16



Dimensions In Millimeters(TSSOP16)										
Symbol:	Α	A1	В	С	C1	D	Q	а	b	
Min:	0.85	0.05	4.90	6.20	4.30	0.40	0°	0.20	0.65 BSC	
Max:	0.95	0.20	5.10	6.60	4.50	0.80	8°	0.25	0.00 880	



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